

Characterization of Fire Hazards of Aged Photovoltaic Balance-of-System Connectors

Eric Schindelholz¹, Benjamin Yang², Kenneth Armijo¹, N. Robert Sorensen¹, Olga Lavrova¹

¹ Sandia National Laboratories, ² Georgia Tech Research Institute

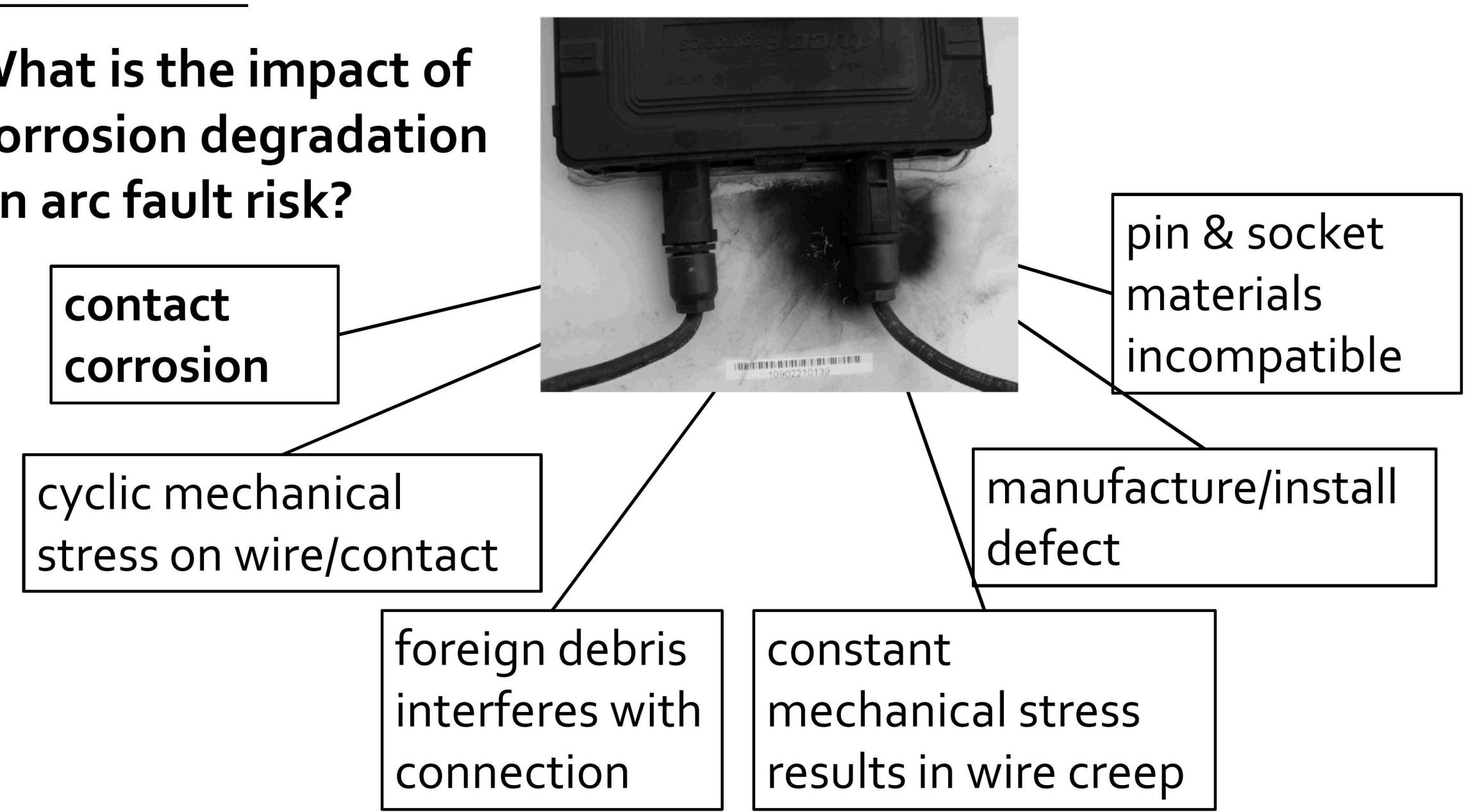
Overview of Research

This work investigates balance of systems (BOS) connector reliability from the perspective of arc fault risk. Accelerated tests were performed on connectors for future development of a reliability model. Thousands of hours of damp heat and atmospheric corrosion tests found BOS connectors to be resilient to corrosion-related degradation. A procedure was also developed to evaluate new and aged connectors for arc fault risk. The measurements show that arc fault risk is dependent on a combination of materials composition and design geometry. Thermal measurements as well as optical emission spectroscopy (OES) were performed to further characterize the arc plasma. Together, the degradation model, arc fault risk assessment technique, and characterization methods can provide operators of photovoltaic installations information necessary to develop a data-driven plan for BOS connector maintenance as well as identify opportunities for arc fault prognostics.

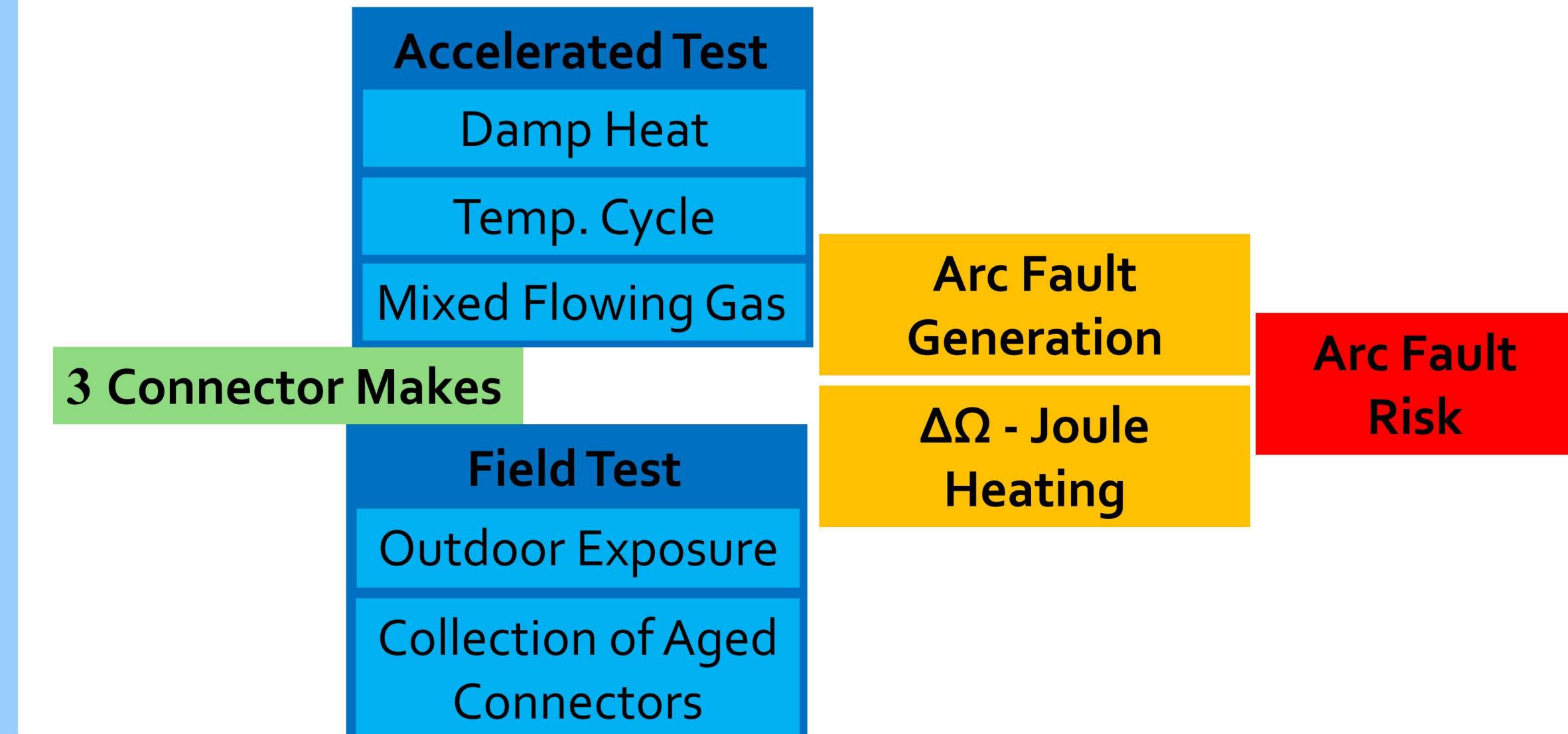
Motivation and Approach

Motivation

What is the impact of corrosion degradation on arc fault risk?

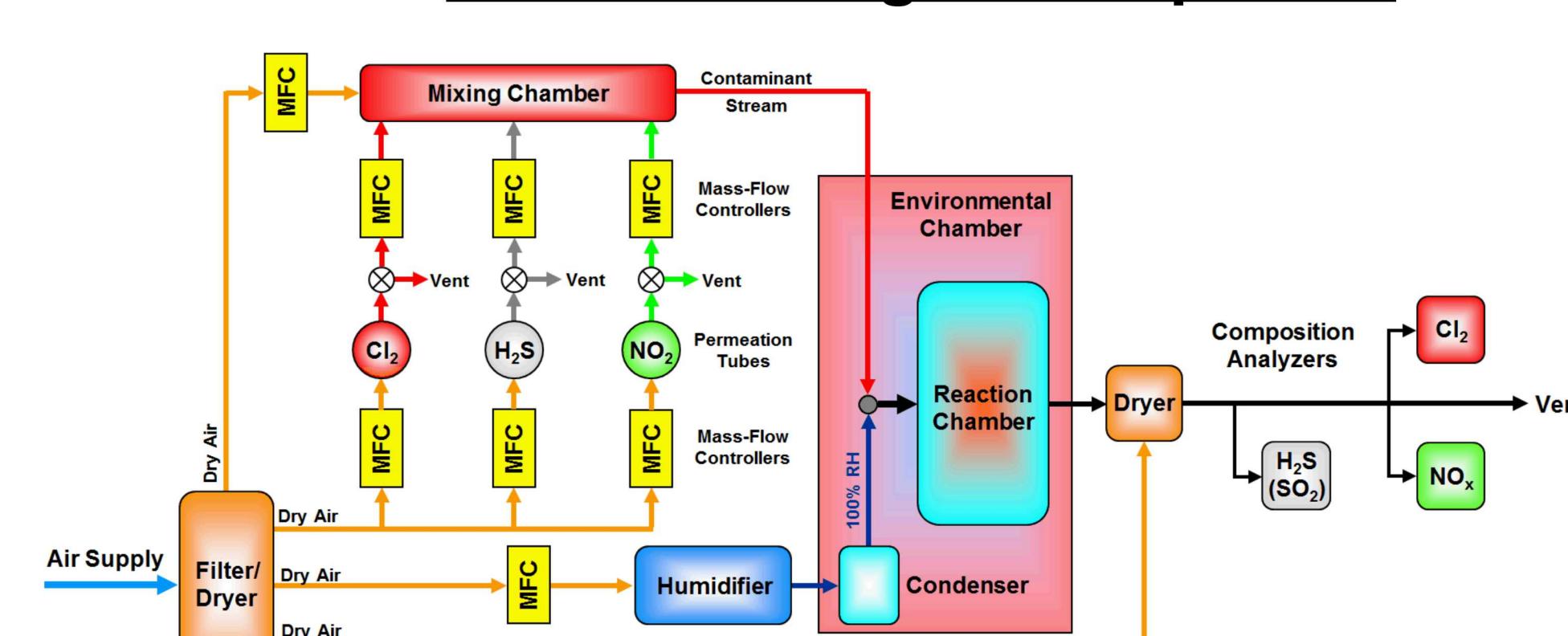


Experimental Approach



Results: Contact Resistance

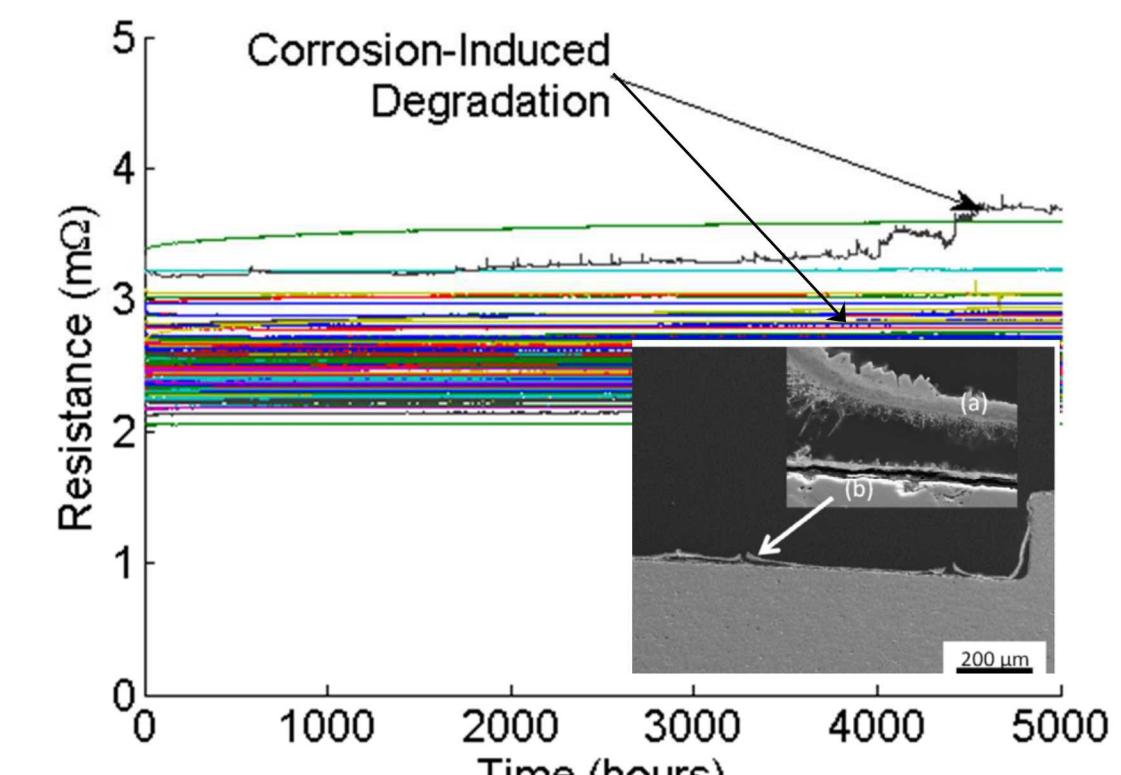
Mixed Flowing Gas Exposure



Field Test at SNL, NM

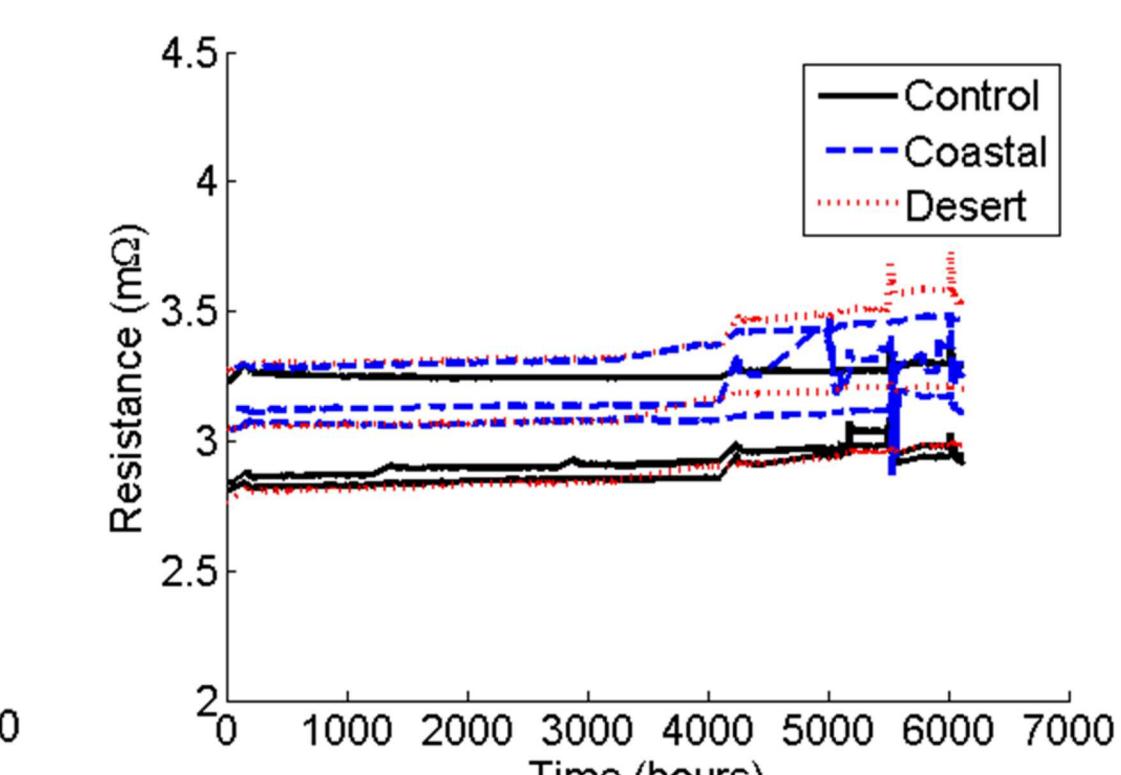


Battelle Class II

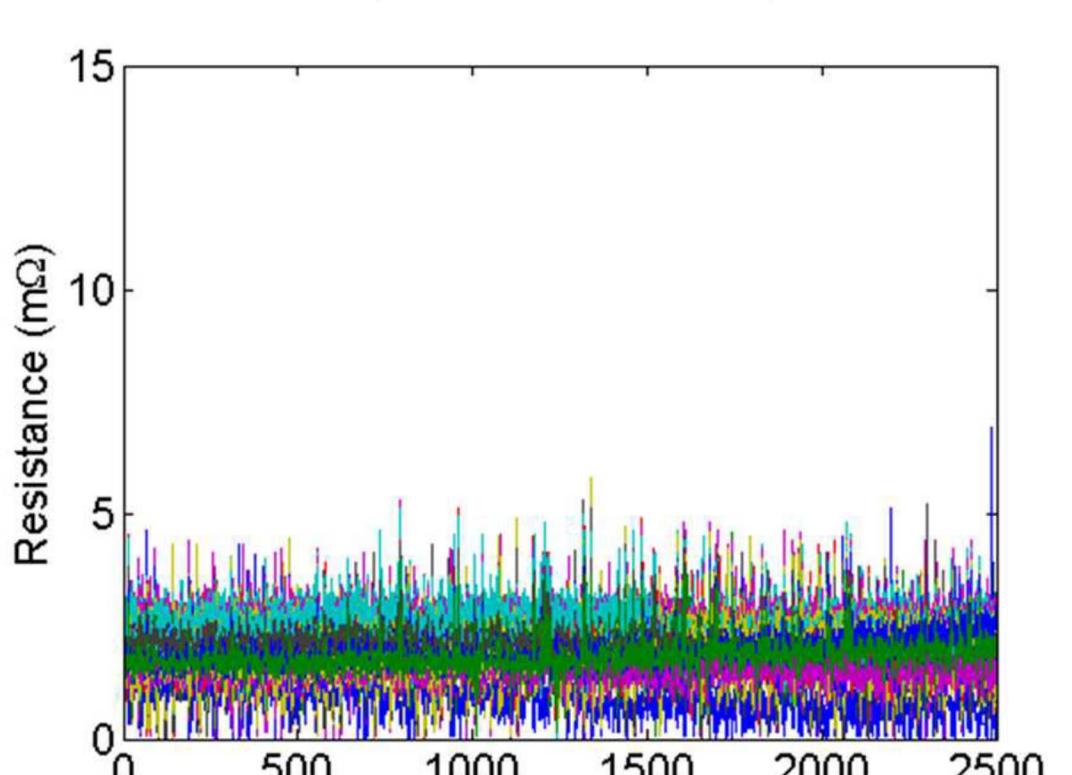


Corrosion of plating, but connectors overall robust to accelerated tests

85°C/85%RH Damp Heat



No discernable difference between non-contaminated (control) and coastal or desert-simulating contaminants

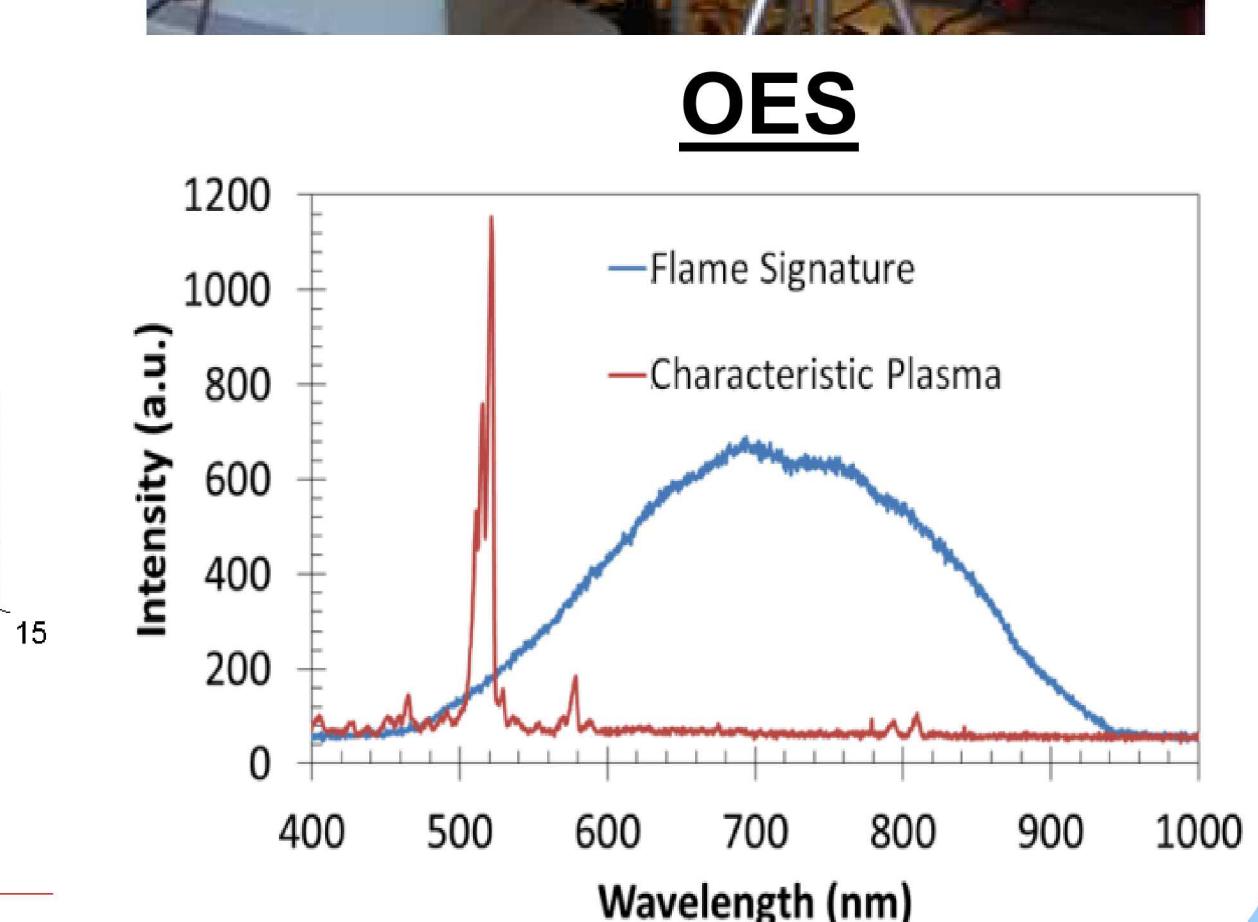
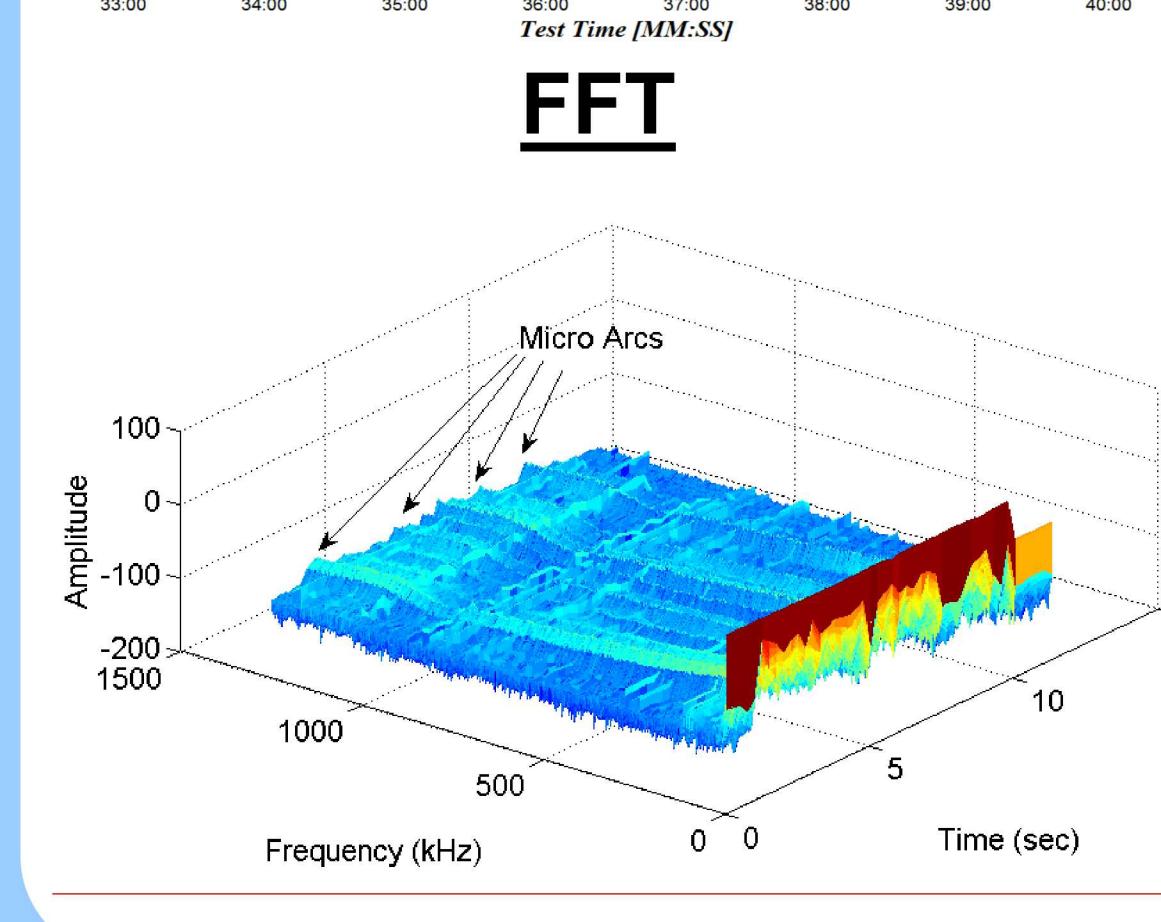
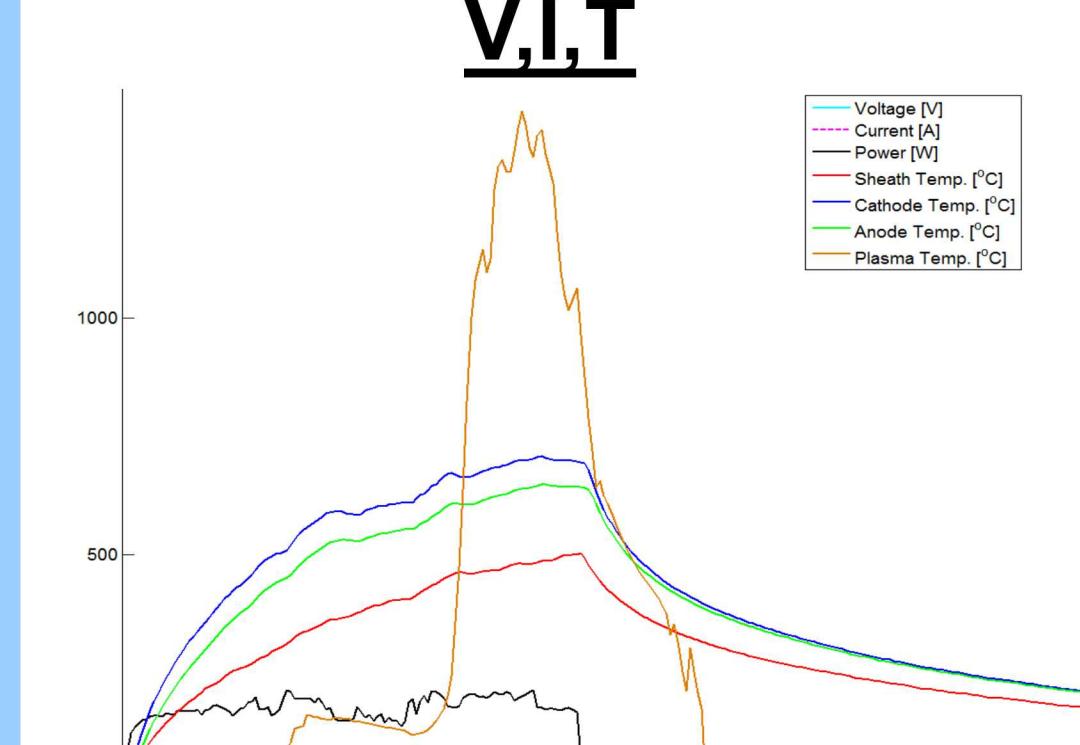
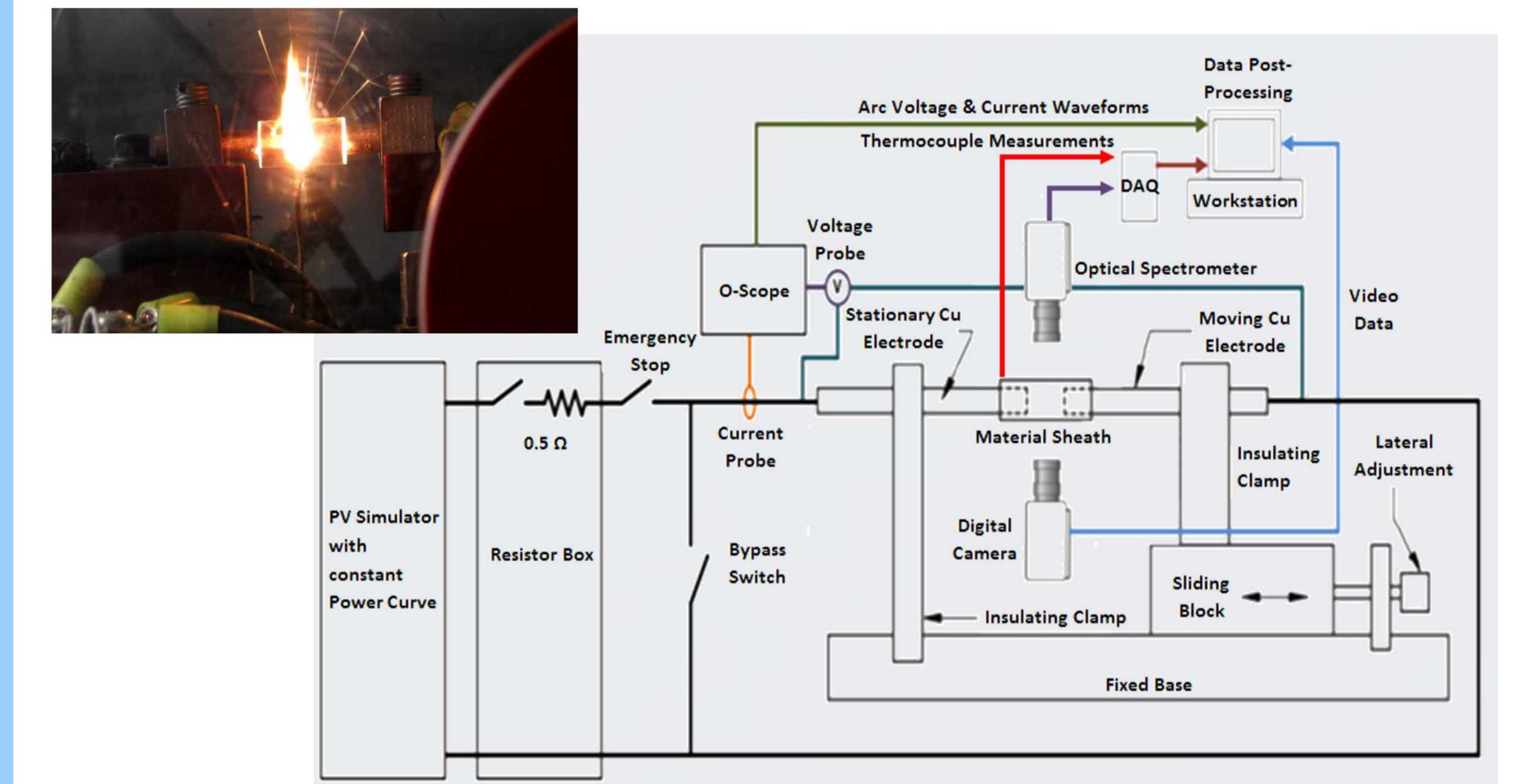


No failures observed in 2500 hours of 51 connectors; test is ongoing

Significance of Work

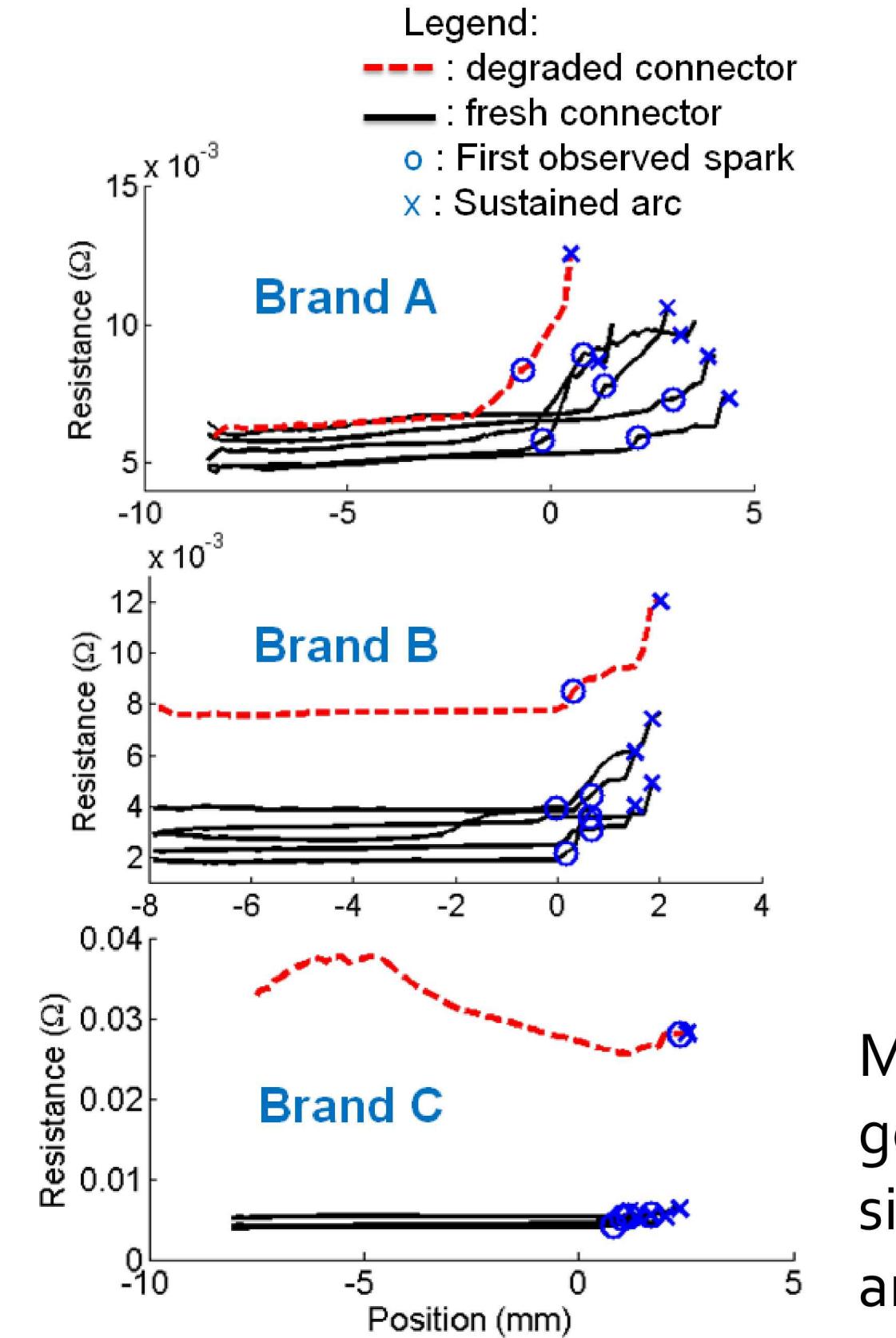
Arc faults are a low-probability but high-consequence hazard in photovoltaic systems. The rate of arc faults is expected to increase as the worldwide installed capacity of photovoltaic systems continues to grow. In the US alone, there have been a number of high profile fires caused by arcing in PV systems. Some of these incidents have been traced to balance of systems (BOS) connectors, with risk and prevention being identified as a critical area to address. The reliability of BOS connectors has been relatively uncharacterized beyond qualification tests.

Arc Fault Experimental Platform

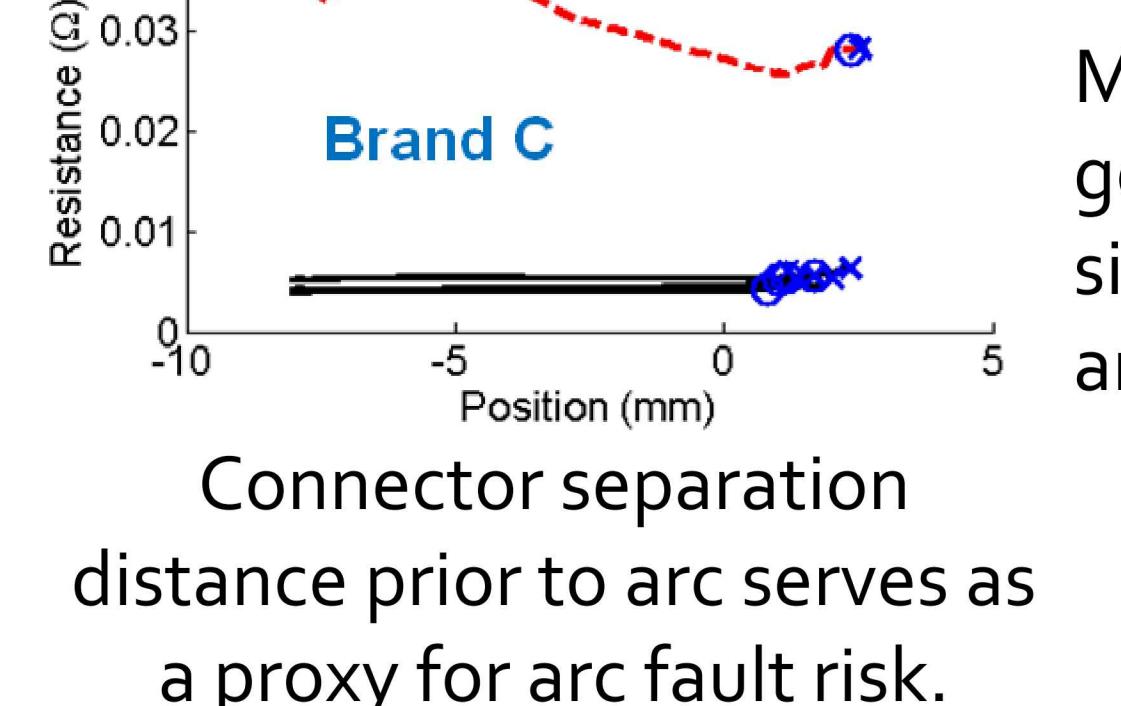


Results: Arc Fault Generation

Temperature

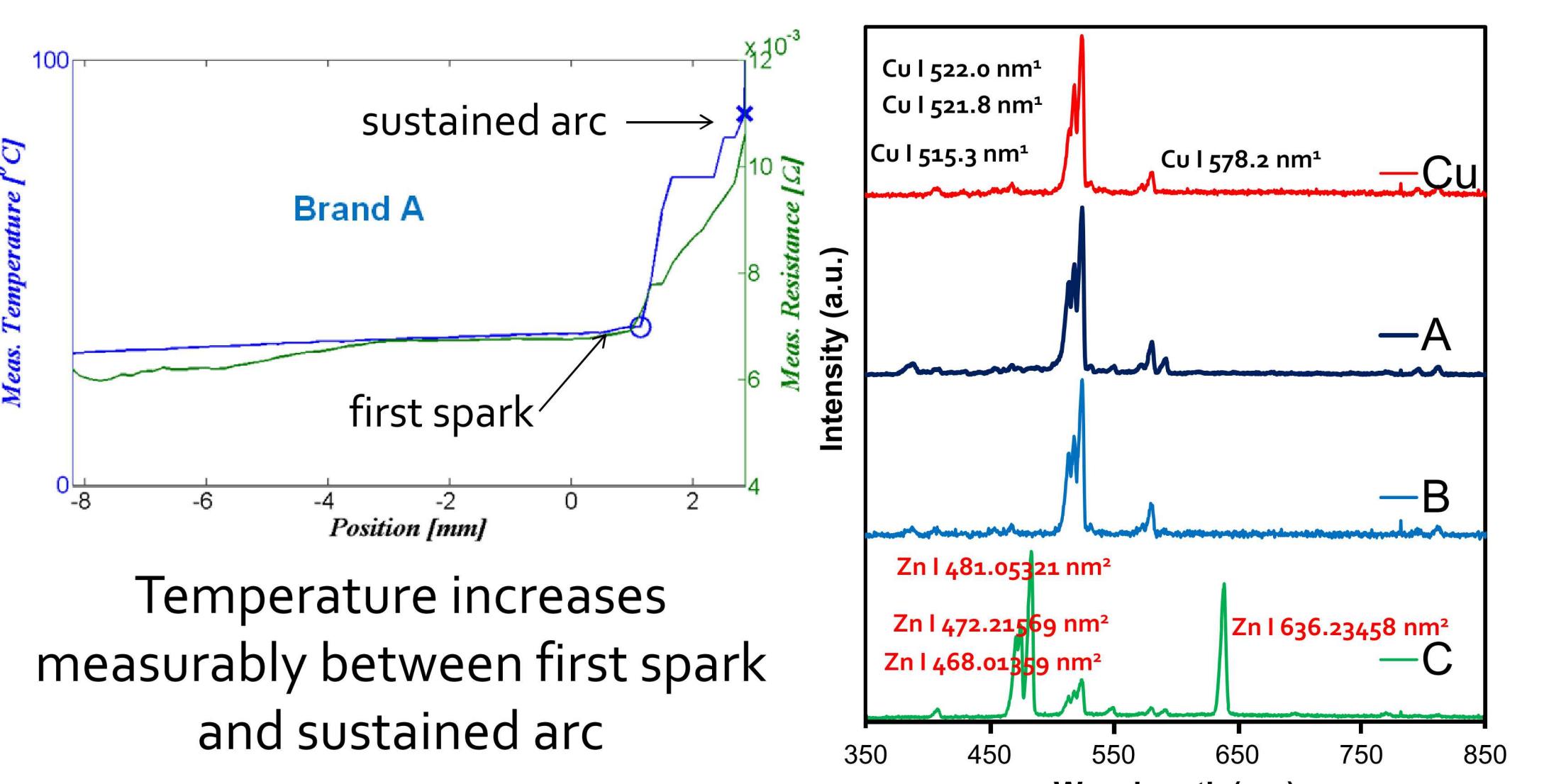


Temperature increases measurably between first spark and sustained arc



Connector separation distance prior to arc serves as a proxy for arc fault risk

OES Analysis



1. S. S. Golani, 35th EPS Conference on Plasma Phys., Heraklion, 9-13 June 2008 ECA Vol.33D, p.3-6 (2008).
2. J. E. Samoray and W. C. Martin, J. Phys. Chem. Ref. Data 34, 4 (2005).

Spectra can identify connectors with similar composition (A and B) vs. one containing other elements (C). Can potentially measure electron plasma temperature

Conclusions

- BOS connectors robust to corrosion-related accelerated tests examined thus far
- Procedure to evaluate arc fault risk of connectors established
- Arc fault risk likely dependent on several factors, such as geometry and composition
- Temperature and emission spectrum analysis can reveal additional information about underlying degradation and arc fault processes